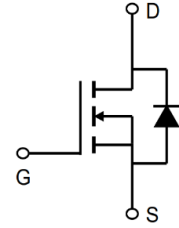


200V N-Channel Enhancement Mode MOSFET

Description

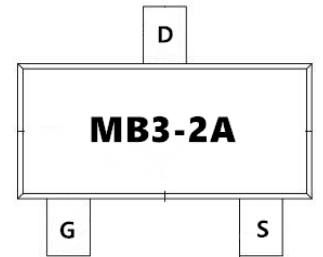
The AP2N20MI is silicon N-channel Enhanced VDMOSFETs, is obtained by the self-aligned planar Technology which reduce the conduction loss, improve switching performance and enhance the avalanche energy. The transistor can be used in various power switching circuit for system



General Features

$V_{DS} = 200V, I_D = 2A$

$R_{DS(ON)} < 1800m\Omega @ V_{GS} = 10V$



Application

LED dimming

Emergency lamp



Package Marking and Ordering Information

Product ID	Pack	Marking	Qty(PCS)
AP2N20MI	SOT-23-3L	MB3-2A	3000

Absolute Maximum Ratings (TC=25°C unless otherwise noted)

Symbol	Parameter	Limit	Unit
V _{DS}	Drain-Source Voltage	200	V
V _{GS}	Gate-Source Voltage	±20	V
I _D	Drain Current-Continuous	2	A
I _{DM}	Drain Current-Pulsed (Note 1)	10	A
P _D	Maximum Power Dissipation	3	W
T _J , T _{STG}	Operating Junction and Storage Temperature Range	-55 To 150	°C
R _{θJA}	Thermal Resistance, Junction-to-Ambient (Note 2)	41.7	°C/W

200V N-Channel Enhancement Mode MOSFET

Electrical Characteristics (T_J=25 °C, unless otherwise noted)

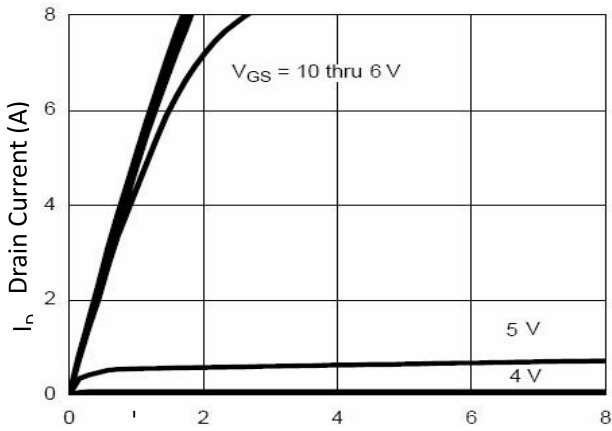
Symbol	Parameter	Condition	Min	Typ	Max	Unit
BV _{DSS}	Drain-Source Breakdown Voltage	V _{GS} =0V, I _D =250μA	200	-	-	V
IDSS	Zero Gate Voltage Drain Current	V _{DS} =200V, V _{GS} =0V	-	-	1	μA
IGSS	Gate-Body Leakage Current	V _{GS} =±20V, V _{DS} =0V	-	-	±100	nA
VGS(th)	Gate Threshold Voltage	V _{DS} =V _{GS} , I _D =250μA	1.0	-	3.0	V
RDS(ON)	Drain-Source On-State Resistance	V _{GS} =10V, I _D =2A	-	1400	1800	mΩ
gFS	Forward Transconductance	V _{DS} =15V, I _D =2A	-	8	-	S
C _{iss}	Input Capacitance	V _{DS} =25V, V _{GS} =0V, F=1.0MHz	-	580	-	PF
C _{oss}	Output Capacitance		-	90	-	PF
C _{rss}	Reverse Transfer Capacitance		-	3	-	PF
td(on)	Turn-on Delay Time	V _{DD} =100V, R _L =15Ω V _{GS} =10V, R _G =2.5Ω	-	10	-	nS
t _r	Turn-on Rise Time		-	12	-	nS
td(off)	Turn-Off Delay Time		-	15	-	nS
t _f	Turn-Off Fall Time		-	15	-	nS
Q _g	Total Gate Charge	V _{DS} =100V, I _D =2A, V _{GS} =10V	-	12	-	nC
Q _{gs}	Gate-Source Charge		-	2.5	-	nC
Q _{gd}	Gate-Drain Charge		-	3.8	-	nC
VSD	Diode Forward Voltage ^(Note 3)	V _{GS} =0V, I _S =2A	-	-	1.2	V
I _S	Diode Forward Current ^(Note 2)		-	-	2	A

Notes:

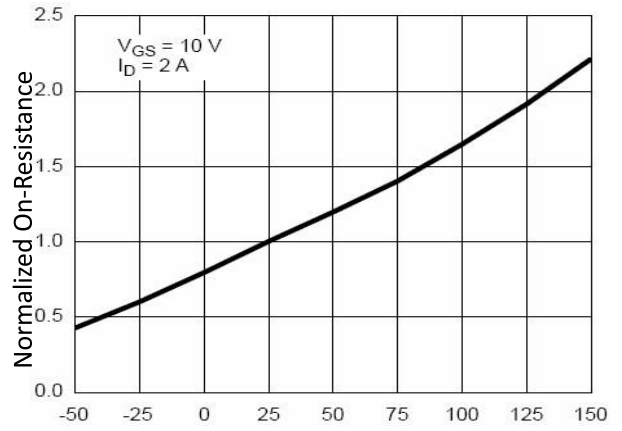
- 1、Repetitive Rating: Pulse width limited by maximum junction temperature.
- 2、Surface Mounted on FR4 Board, t ≤ 10 sec.
- 3、Pulse Test: Pulse Width ≤ 300μs, Duty Cycle ≤ 2%.
- 4、Guaranteed by design, not subject to production

200V N-Channel Enhancement Mode MOSFET

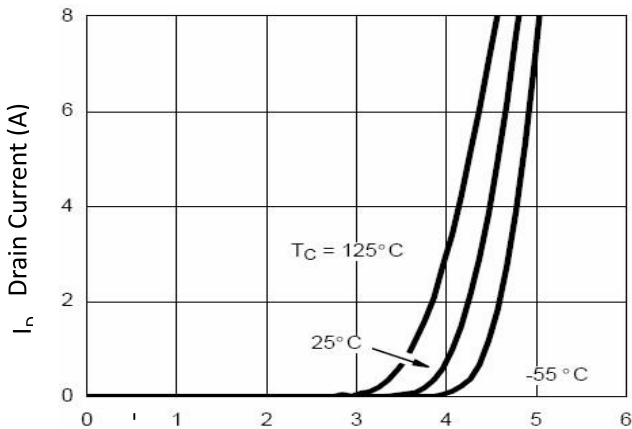
Typical Electrical and Thermal Characteristics (Curves)



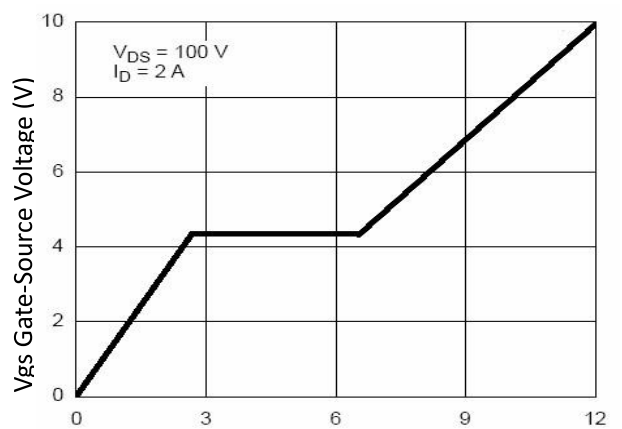
V_{DS} Drain-Source Voltage (V)
Figure 1 Output Characteristics



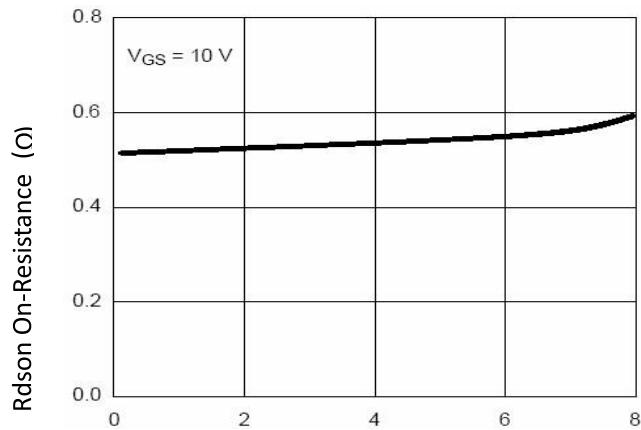
T_J -Junction Temperature ($^{\circ}C$)
Figure 4 $R_{DS(on)}$ -Junction Temperature



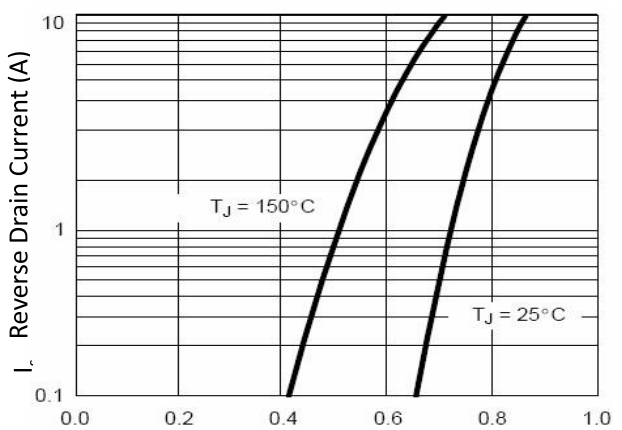
V_{GS} Gate-Source Voltage (V)
Figure 2 Transfer Characteristics



Q_g Gate Charge (nC)
Figure 5 Gate Charge



I_D - Drain Current (A)
Figure 3 $R_{DS(on)}$ - Drain Current



V_{SD} Source-Drain Voltage (V)
Figure 6 Source- Drain Diode Forward

200V N-Channel Enhancement Mode MOSFET

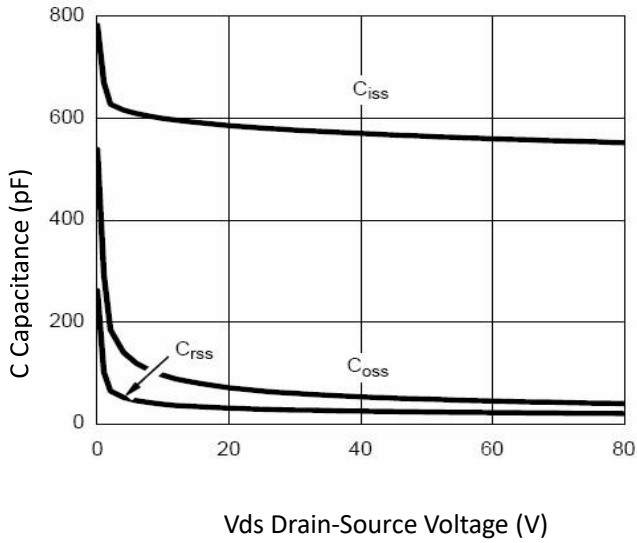


Figure 7 Capacitance vs Vds

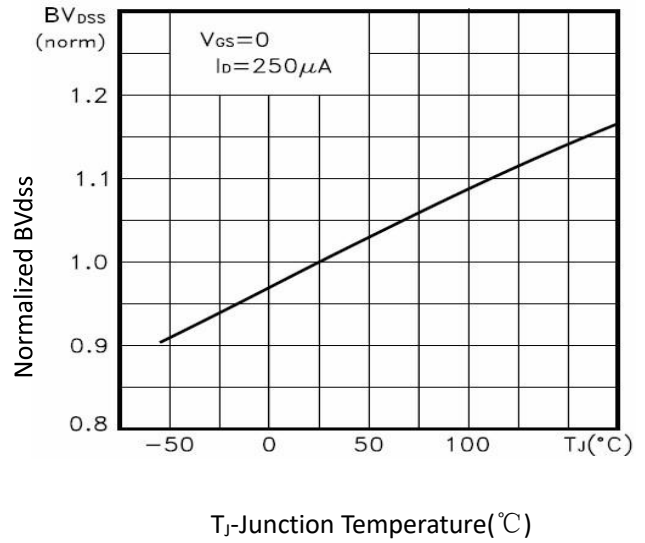


Figure 9 BV_{DSS} vs Junction Temperature

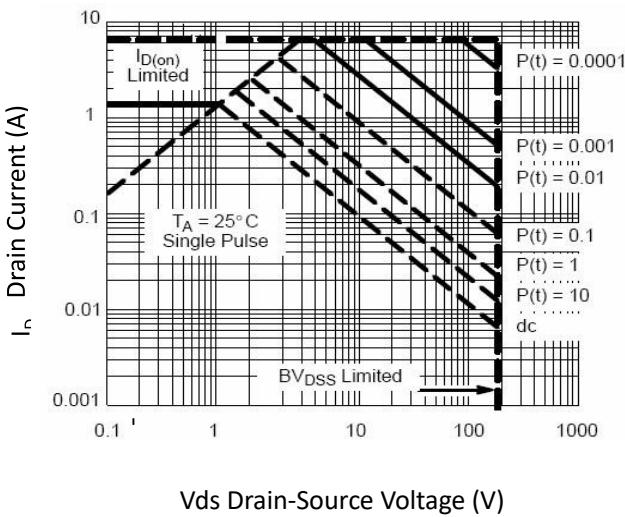


Figure 8 Safe Operation Area

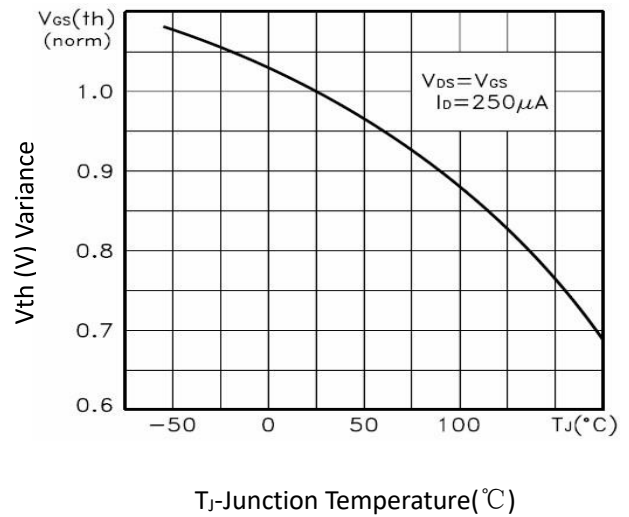


Figure 10 V_{GS(th)} vs Junction Temperature

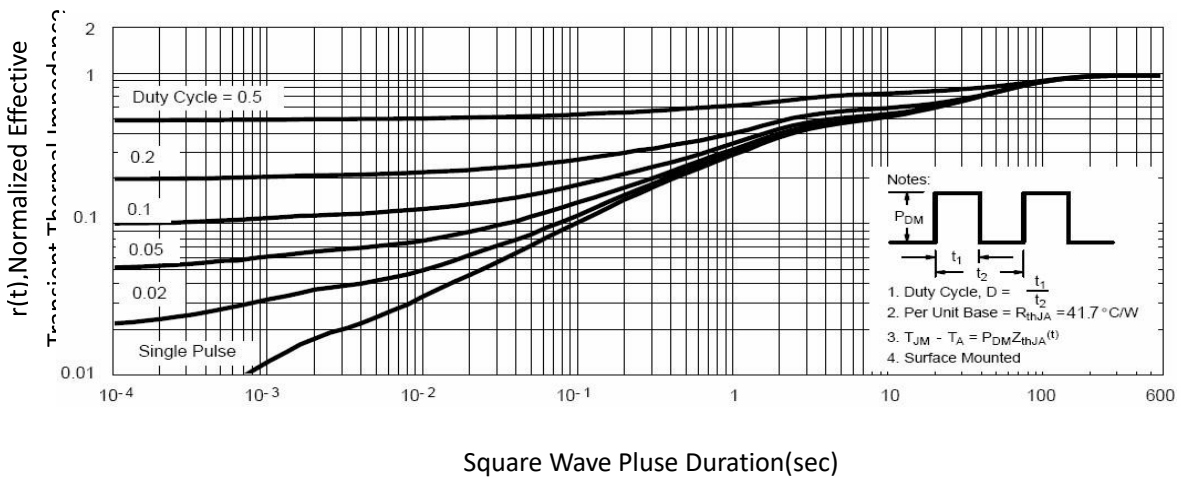
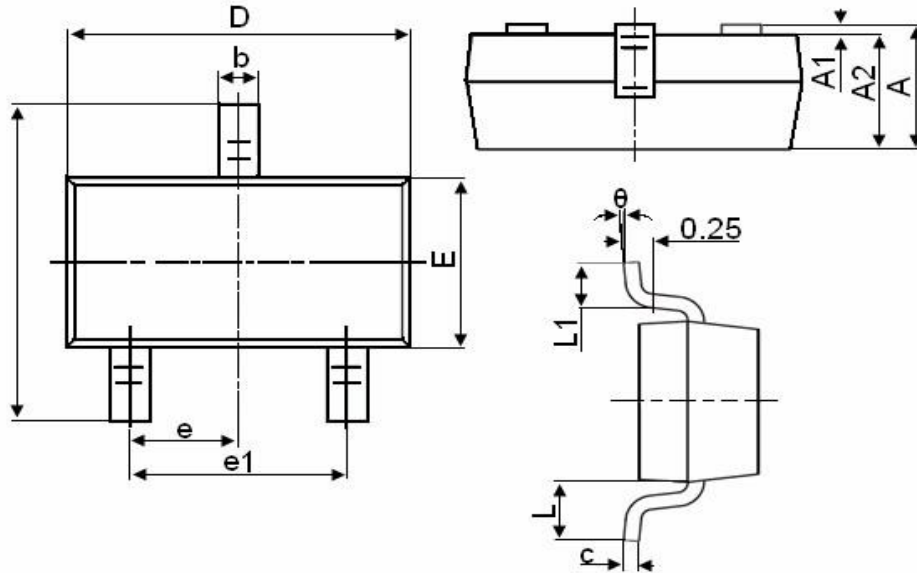


Figure 11 Normalized Maximum Transient Thermal Impedance

Package Mechanical Data: SOT23-3L



Symbol	Dimensions in Millimeters	
	MIN.	MAX.
A	0.900	1.150
A1	0.000	0.100
A2	0.900	1.050
b	0.300	0.500
c	0.080	0.150
D	2.800	3.000
E	1.200	1.400
E1	2.250	2.550
e	0.950TYP	
e1	1.800	2.000
L	0.550REF	
L1	0.300	0.500
θ	0°	8°

200V N-Channel Enhancement Mode MOSFET**Attention**

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200V N-Channel Enhancement Mode MOSFET

Edition	Date	Change
Rve3.2	2018/1/31	Initial release
Rve3.3	2019/12/01	Reduce RDS
Rve3.4	2020/4/01	Reduce VTH

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